

US00D675338S

(12) **United States Design Patent**
Suzuki et al.

(10) **Patent No.:** **US D675,338 S**
(45) **Date of Patent:** **** Jan. 29, 2013**

(54) **SAMPLE RACK**

(75) Inventors: **Kouichi Suzuki**, Hitachinaka (JP);
Nobuo Suzuki, Hitachinaka (JP); **Seiji**
Nomura, Tokai (JP); **Takeshi Setomaru**,
Hitachinaka (JP)

(73) Assignee: **Hitachi High-Technologies**
Corporation, Tokyo (JP)

(**) Term: **14 Years**

(21) Appl. No.: **29/309,874**

(22) Filed: **Oct. 30, 2008**

(30) **Foreign Application Priority Data**

Jul. 18, 2008 (JP) 2008-018582

(51) **LOC (9) Cl.** **24-02**

(52) **U.S. Cl.** **D24/229**

(58) **Field of Classification Search** D24/108,
D24/127, 128, 216, 224, 227-332; 422/63-64,
422/99-104, 250, 266, 297, 300, 476, 561-562;
211/69, 71-72, 74, 71.01, 60.1; 206/443
See application file for complete search history.

(56) **References Cited**

U.S. PATENT DOCUMENTS

D333,522	S	*	2/1993	Gianino		D24/229
5,186,339	A	*	2/1993	Heissler		211/74
D382,346	S	*	8/1997	Buhler et al.		D24/230
D413,391	S	*	8/1999	Lapeus et al.		D24/227
D413,677	S	*	9/1999	Dumitrescu et al.		D24/227
D417,009	S	*	11/1999	Boyd		D24/229
D420,747	S	*	2/2000	Dumitrescu et al.		D24/227
D421,130	S	*	2/2000	Cohen et al.		D24/230
D428,497	S	*	7/2000	Lapeus et al.		D24/227
6,123,205	A	*	9/2000	Dumitrescu et al.		422/562
D433,759	S	*	11/2000	Mathis et al.		D24/227
D481,133	S	*	10/2003	Blouin et al.		D24/216

D484,989	S	*	1/2004	Gebrian		D24/230
D500,363	S	*	12/2004	Fanning et al.		D24/229
7,000,785	B2	*	2/2006	Jafari et al.		422/561

(Continued)

FOREIGN PATENT DOCUMENTS

JP D878520 9/1993

(Continued)

OTHER PUBLICATIONS

Sample Rack (Parts No. E001-E020), Hitachi High-Technologies Corporation, before 2003.

Primary Examiner — T. Chase Nelson

Assistant Examiner — Mark Cavanna

(74) *Attorney, Agent, or Firm* — Antonelli, Terry, Stout & Kraus, LLP.

(57) **CLAIM**

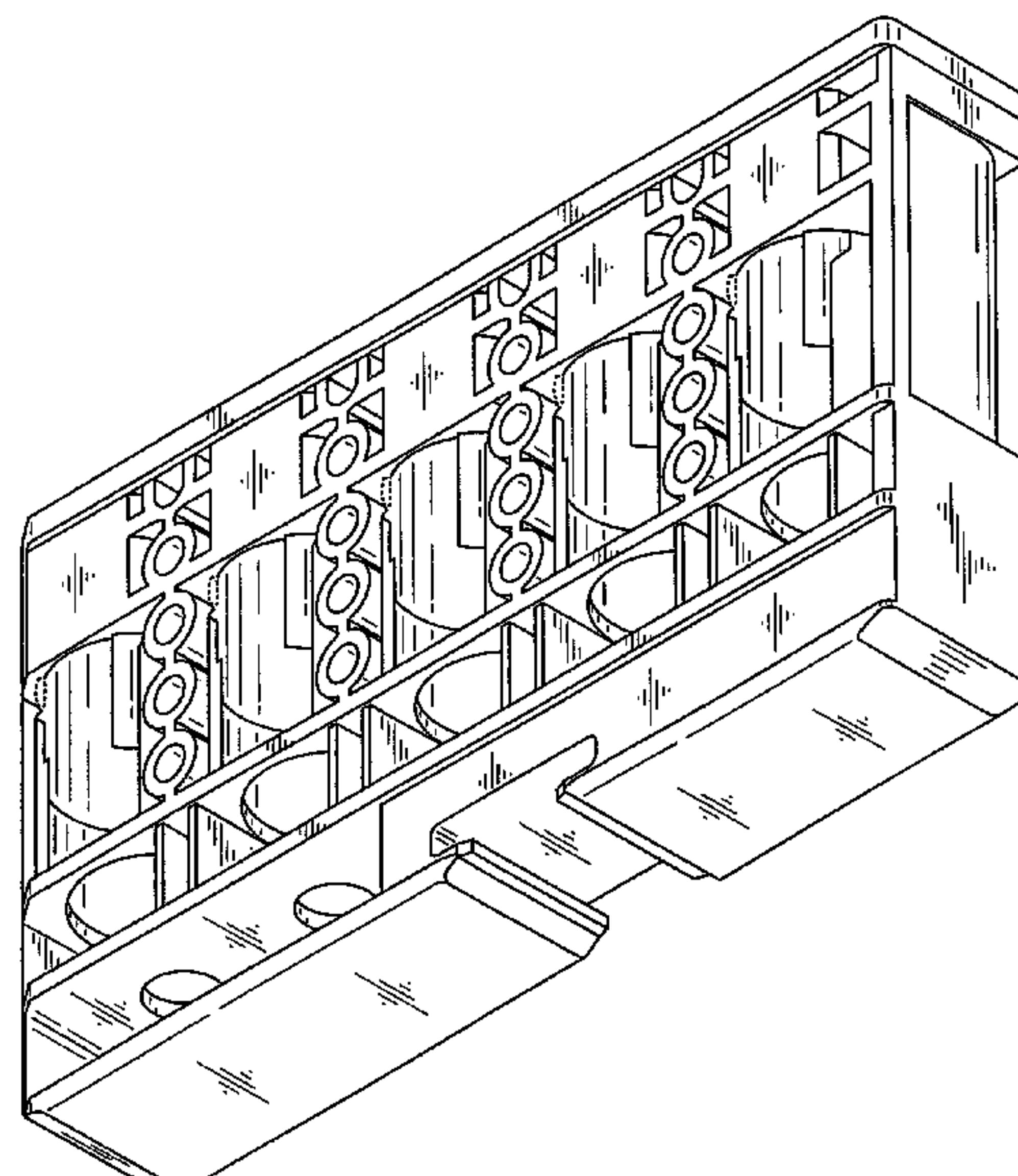
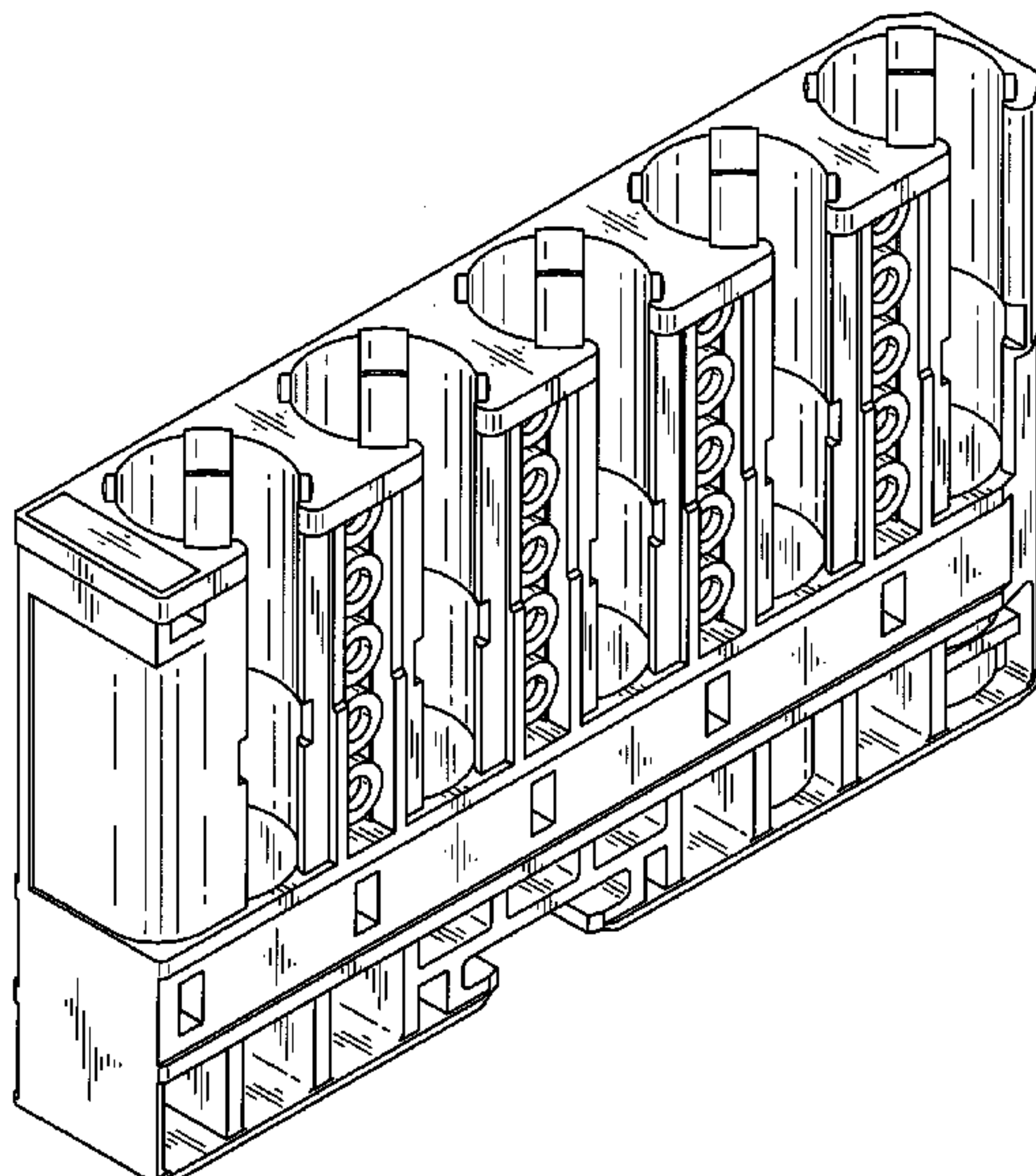
We claim the ornamental design for a sample rack, as shown and described.

DESCRIPTION

FIG. 1 is a front, top and left side perspective view of a sample rack showing our new design;
FIG. 2 is a rear, bottom and left side perspective view thereof;
FIG. 3 is a front elevational view thereof;
FIG. 4 is a rear elevational view thereof;
FIG. 5 is a top plan view thereof;
FIG. 6 is a bottom plan view thereof;
FIG. 7 is a left side elevational view thereof;
FIG. 8 is a right side elevational view thereof; and,
FIG. 9 is an enlarged view of the portion shown in BOX 9 in FIG. 5 thereof.

The broken lines are included to outline in FIG. 5 the border for the enlarged view shown in FIG. 9, and the remaining broken lines are included for the purpose of illustrating unclaimed portions of the sample rack that form no part of the claimed design.

1 Claim, 7 Drawing Sheets



US D675,338 S

Page 2

U.S. PATENT DOCUMENTS

D533,947	S	*	12/2006	Gomm et al.		D24/227
D534,280	S	*	12/2006	Gomm et al.		D24/224
D595,423	S	*	6/2009	Johansson et al.		D24/229
D596,312	S	*	7/2009	Giraud et al.		D24/230
D596,758	S	*	7/2009	Constable		D24/230
D598,566	S	*	8/2009	Allaer		D24/230

D603,524	S	*	11/2009	Suzuki et al.		D24/229
D618,820	S	*	6/2010	Wilson et al.		D24/227
D637,737	S	*	5/2011	Wilson et al.		D24/230

FOREIGN PATENT DOCUMENTS

JP	2006-292696	10/2006
----	-------------	---------

* cited by examiner

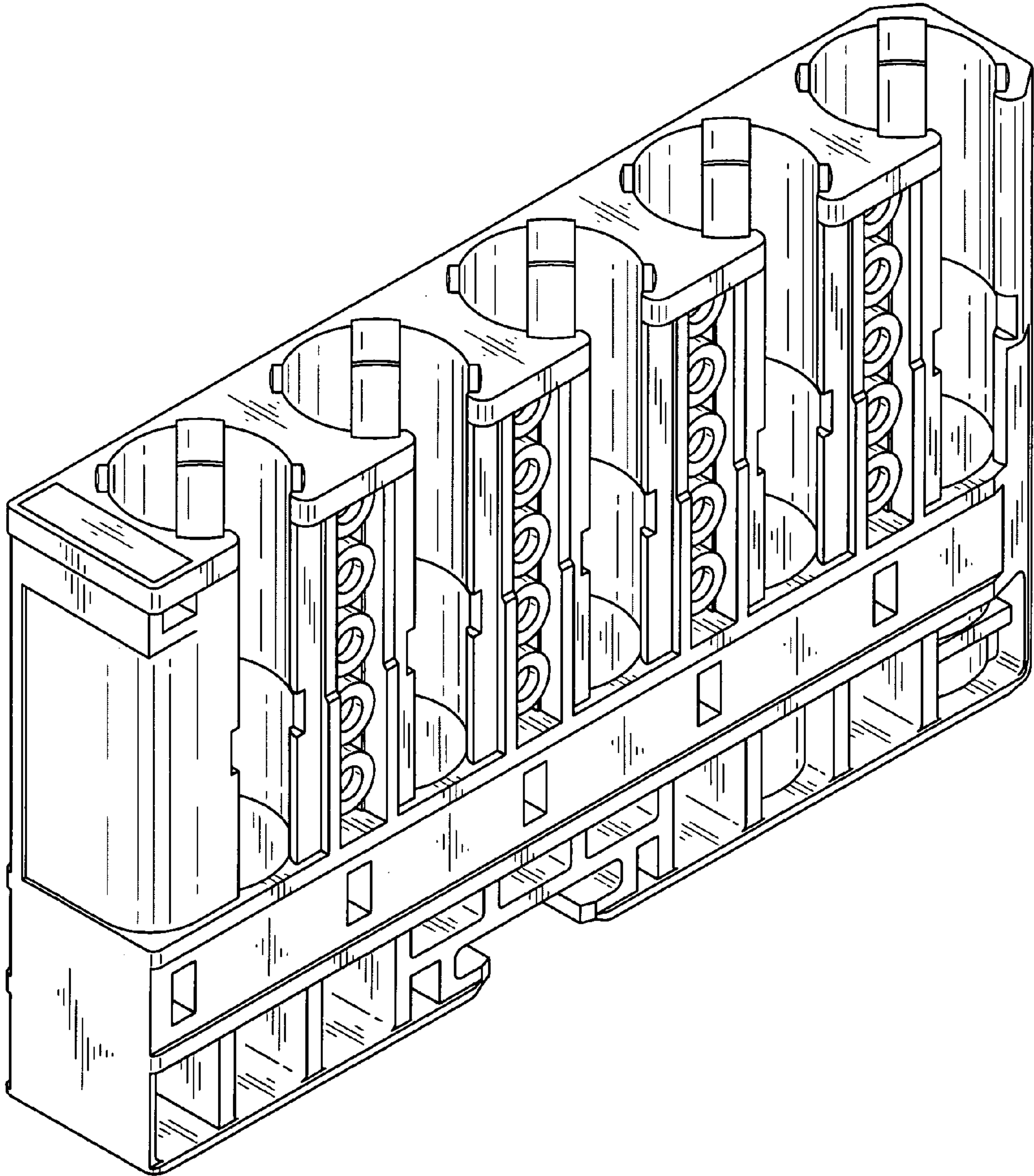


FIG. 1

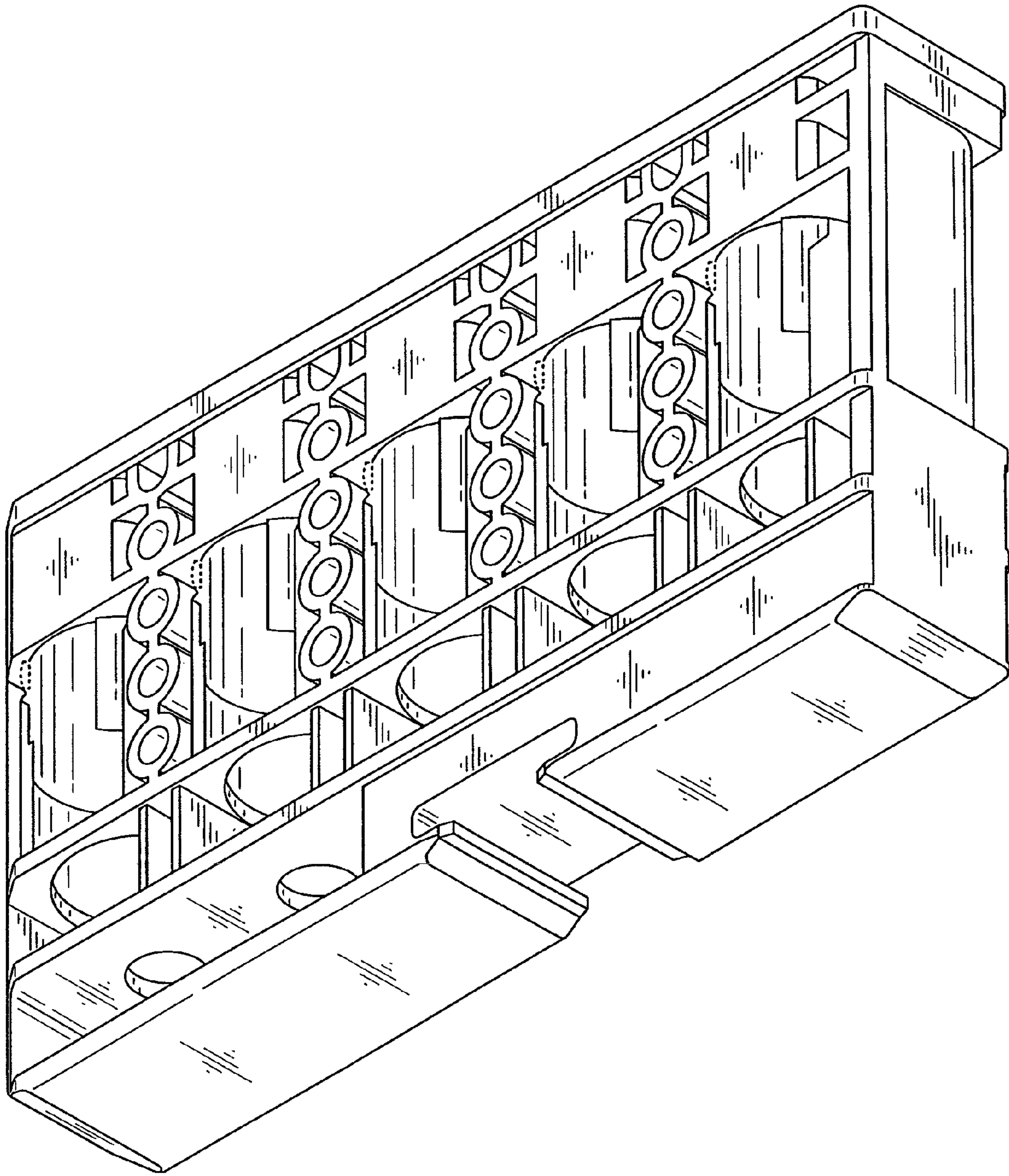


FIG. 2

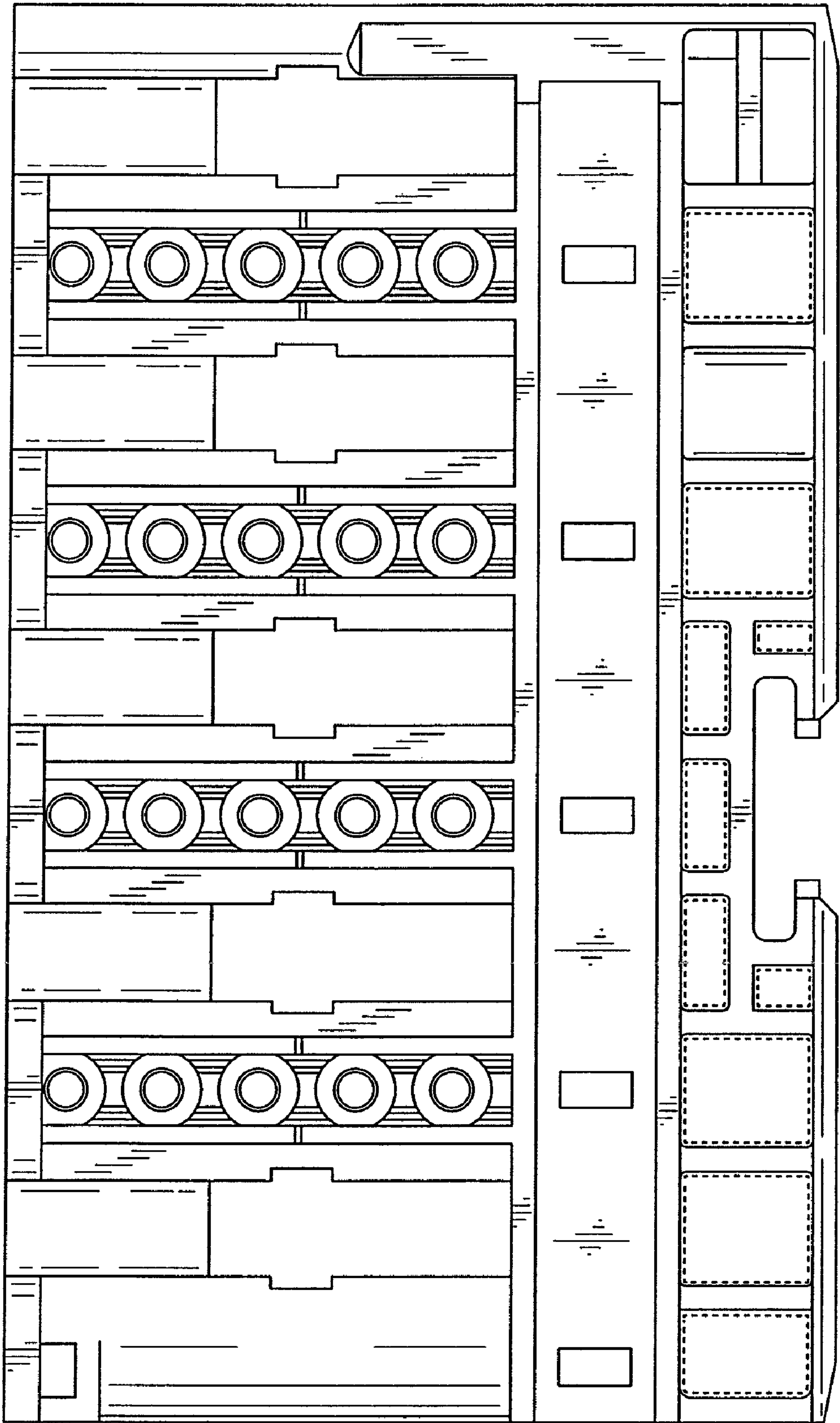


FIG. 3

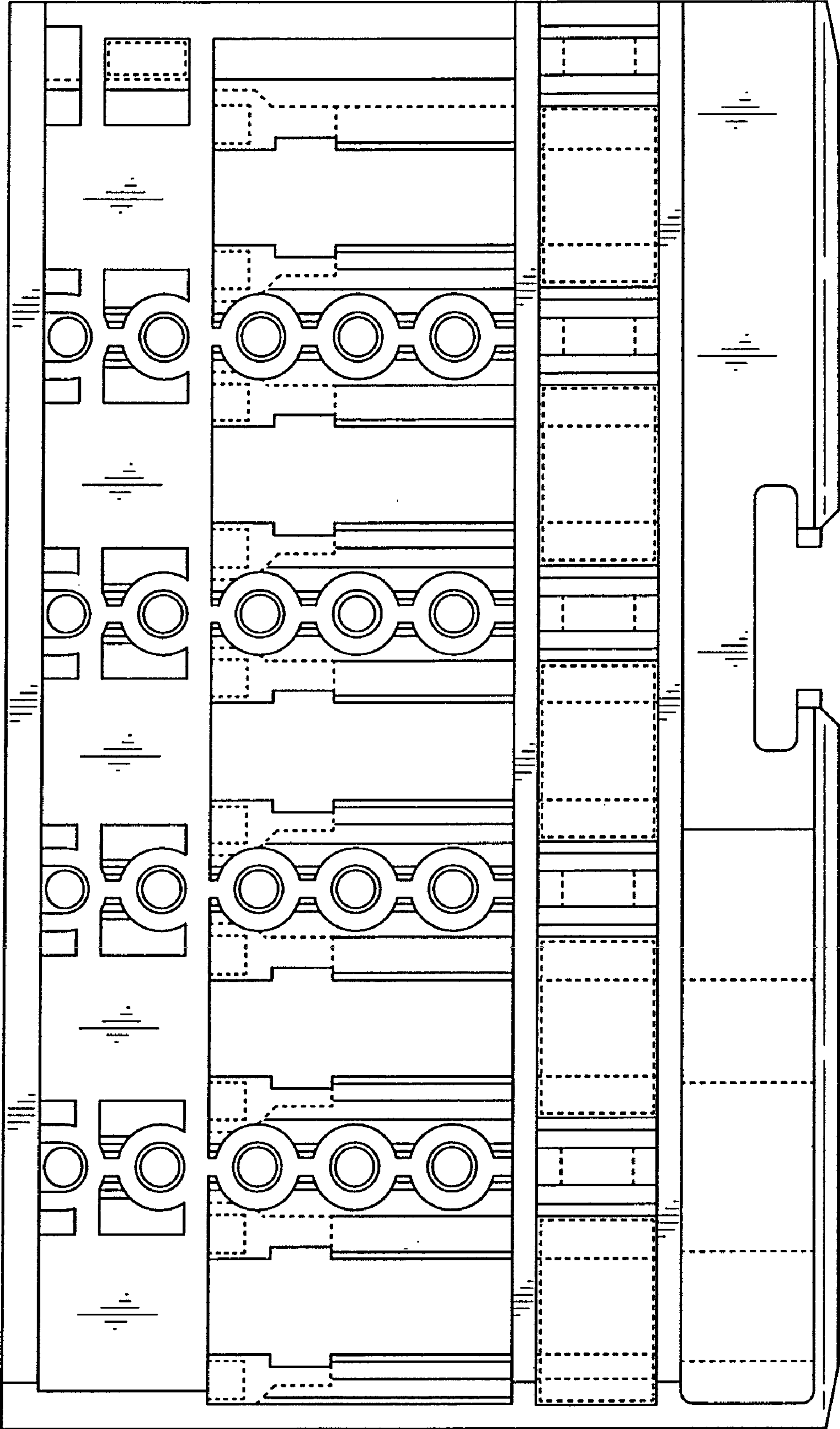


FIG. 4

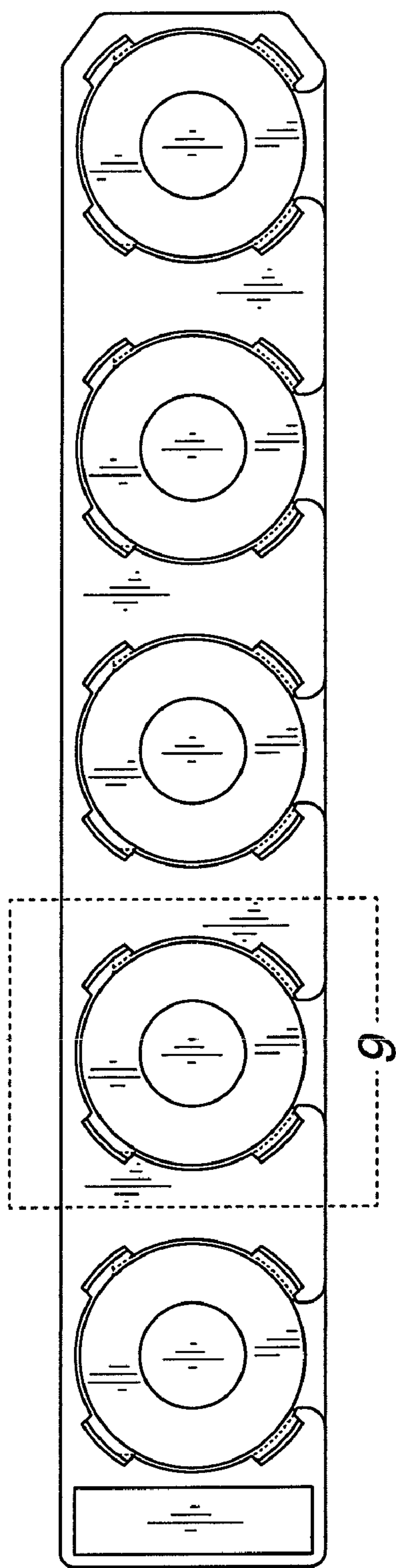


FIG. 5

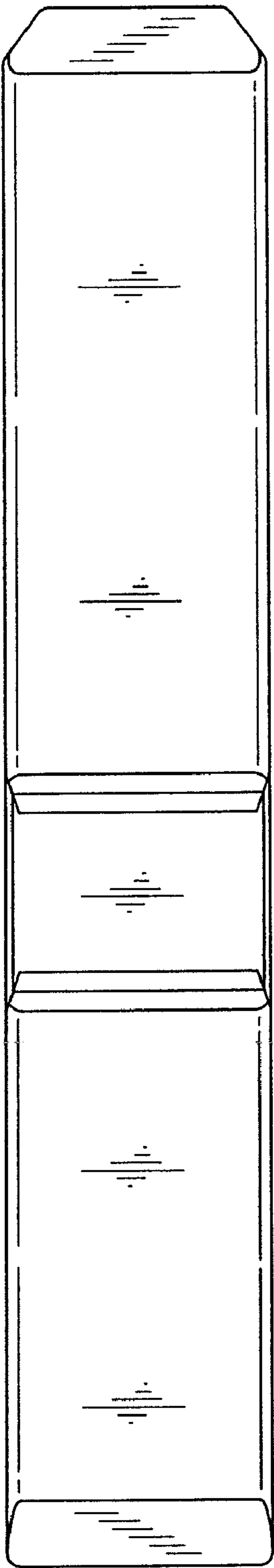


FIG. 6

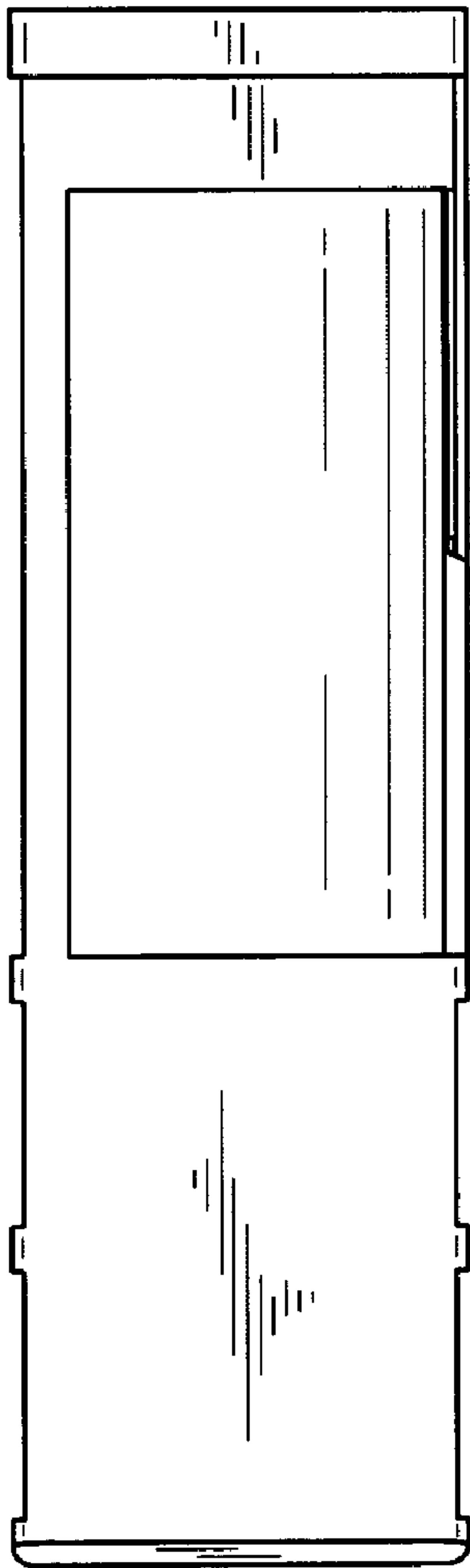


FIG. 7

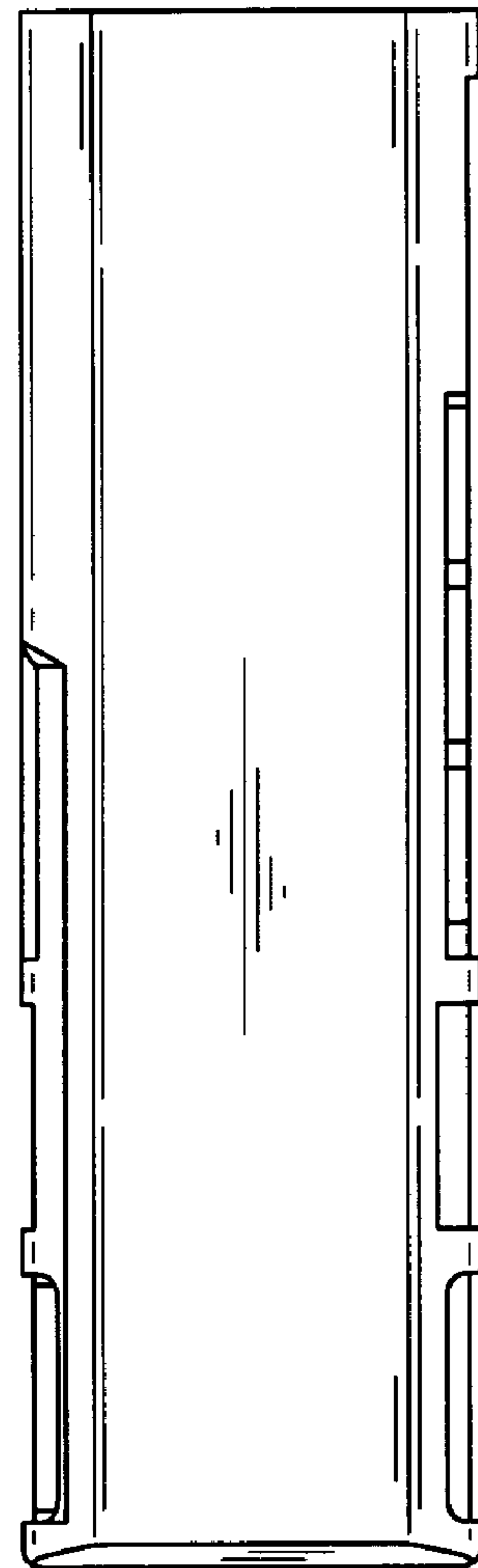


FIG. 8

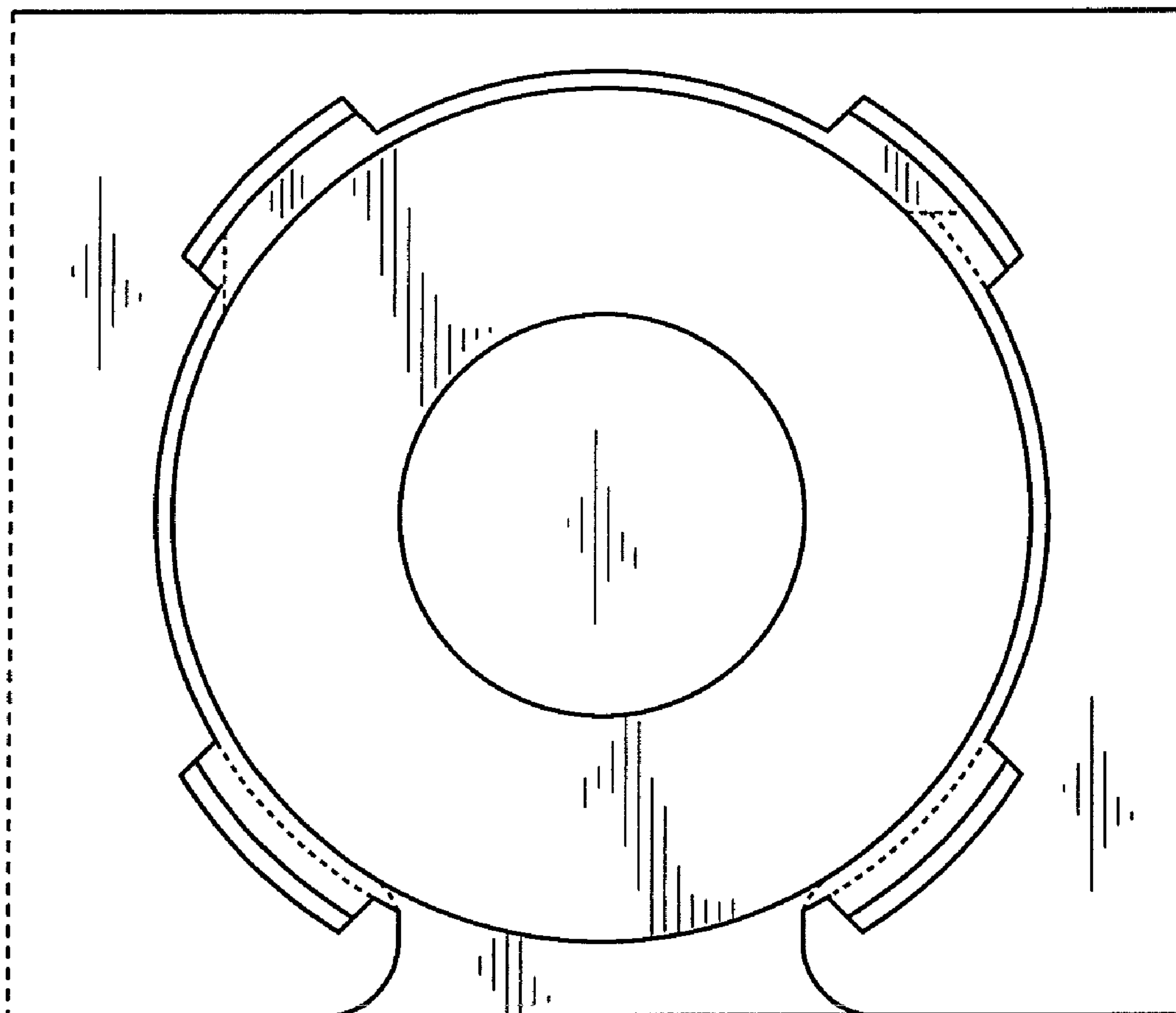


FIG. 9